

May 2000



# FQA19N20L

## 200V LOGIC N-Channel MOSFET

## **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, motor control.

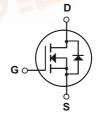
#### **Features**

- 25A, 200V, R<sub>DS(on)</sub> = 0.14Ω @V<sub>GS</sub> = 10 V
- Low gate charge (typical 27 nC)
- Low Crss (typical 30 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- Low level gate drive requirement allowing direct operation from logic drivers



GDS

TO-3P FQA Series



## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQA19N20L	Units
V <sub>DSS</sub>	Drain-Source Voltage	1 9	200	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		25	Α
	- Continuous (T <sub>C</sub> = 100°C)		15.8	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	100	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	25	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		19	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		5.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		190	W
	- Derate above 25°C		1.52	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
Tı	Maximum lead temperature for soldering purposes,		300	°C
'L	1/8" from case for 5 seconds	from case for 5 seconds		

# Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.66	°C/W
R <sub>0CS</sub>	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	200			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.16		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V			1	μА
		V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C			10	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics		•			
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1.0		2.0	V
R <sub>DS(on)</sub>	Static Drain-Source	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 12.5 A		0.11	0.14	
D3(0II)	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 12.5 \text{ A}$ (Note 4)		0.12	0.15	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 12.5 A		20		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		1700 220	2200 290	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1.0 WILL		30	40	pF
	ing Characteristics	T		35	90	no
	Turn-On Delay Time			ან	80	ns
	Turn On Bigg Time	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 21 A,		200	610	no
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		300	610	ns
t <sub>r</sub>	Turn-Off Delay Time			130	270	ns
t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-Off Delay Time Turn-Off Fall Time	$R_G = 25 \Omega$ (Note 4, 5)		130 180	270 370	ns ns
$\begin{array}{c} t_r \\ t_{d(off)} \\ t_f \\ Q_g \end{array}$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 160 \text{ V}, I_D = 21 \text{ A},$		130 180 27	270	ns ns nC
t <sub>d(off)</sub> t <sub>f</sub> Q <sub>g</sub> Q <sub>gs</sub>	Turn-Off Delay Time Turn-Off Fall Time	$R_G = 25 \Omega$ (Note 4, 5)		130 180	270 370 35	ns ns
$\begin{array}{c} t_r \\ t_{d(off)} \\ t_f \\ Q_g \\ Q_{gs} \\ Q_{gd} \\ \end{array}$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 160 \text{ V}, I_D = 21 \text{ A},$ $V_{GS} = 5 \text{ V}$ (Note 4, 5)		130 180 27 5.8	270 370 35	ns ns nC
$t_r$ $t_{d(off)}$ $t_f$ $Q_g$ $Q_{gs}$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$R_{G} = 25 \ \Omega $ (Note 4, 5) $V_{DS} = 160 \ V, I_{D} = 21 \ A, $ (Note 4, 5) $V_{GS} = 5 \ V $ (Note 4, 5) and Maximum Ratings		130 180 27 5.8	270 370 35	ns ns nC
$t_r$ $t_{d(off)}$ $t_f$ $Q_g$ $Q_{gs}$ $Q_{gd}$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 160 \text{ V}, I_D = 21 \text{ A}, V_{GS} = 5 \text{ V}$ (Note 4, 5)  and Maximum Ratings of the Forward Current		130 180 27 5.8 11.2	270 370 35 	ns ns nC nC
$t_r$ $t_{d(off)}$ $t_f$ $Q_g$ $Q_{gs}$ $Q_{gd}$ Drain-S $l_S$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge  Source Diode Characteristics as Maximum Continuous Drain-Source Dio	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 160 \text{ V}, I_D = 21 \text{ A}, V_{GS} = 5 \text{ V}$ (Note 4, 5)  and Maximum Ratings of the Forward Current		130 180 27 5.8 11.2	270 370 35   25	ns ns nC nC
$t_r$ $t_{d(off)}$ $t_f$ $Q_g$ $Q_{gs}$ $Q_{gd}$ Drain-S	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge  Source Diode Characteristics and Maximum Continuous Drain-Source Diode Faxing Diode Faxing Diode Faxing Delay Time Diode Faxing Delay Time Diode Faxing Delay Time Delay	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 160 \text{ V}, I_D = 21 \text{ A}, V_{GS} = 5 \text{ V}$ (Note 4, 5)  and Maximum Ratings  the Forward Current  Forward Current		130 180 27 5.8 11.2	270 370 35   25 100	ns ns nC nC nC A A

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.6mH, I<sub>AS</sub> = 25A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  21A, di/dt  $\leq$  300A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

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# **Typical Characteristics**

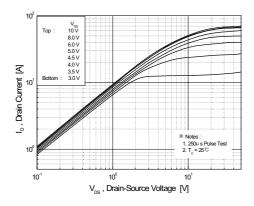


Figure 1. On-Region Characteristics

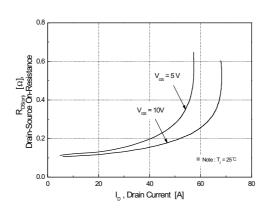


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

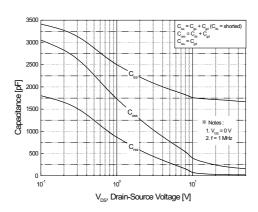


Figure 5. Capacitance Characteristics

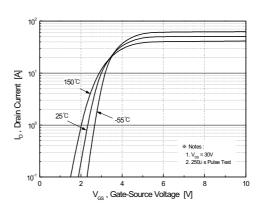


Figure 2. Transfer Characteristics

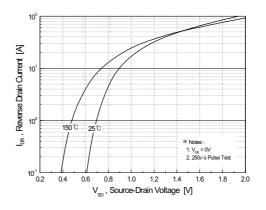


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

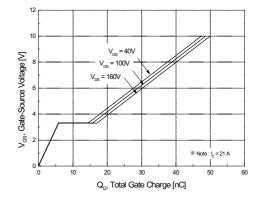
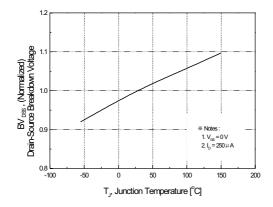


Figure 6. Gate Charge Characteristics

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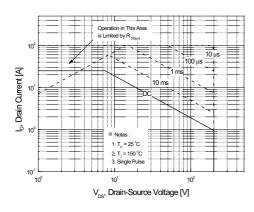
# Typical Characteristics (Continued)



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Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



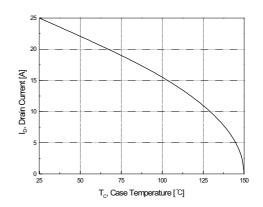


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

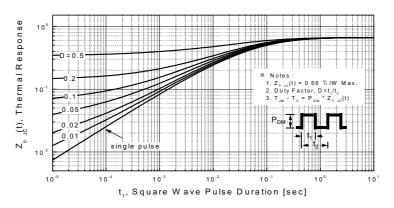
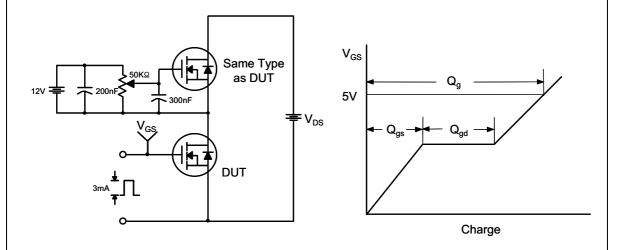


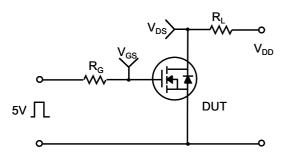
Figure 11. Transient Thermal Response Curve

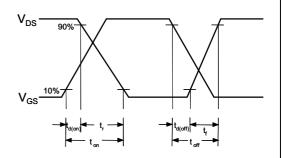
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## **Gate Charge Test Circuit & Waveform**

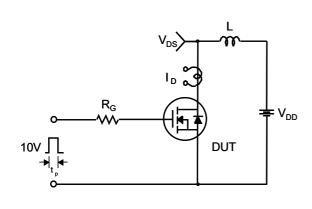


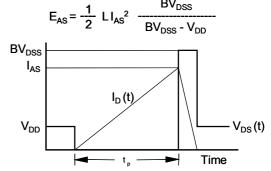
## **Resistive Switching Test Circuit & Waveforms**



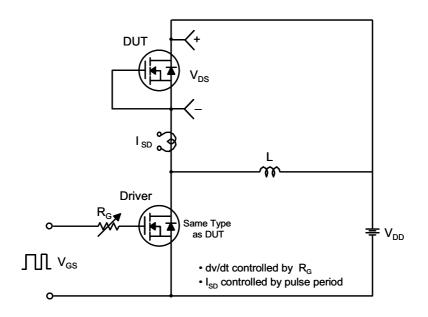


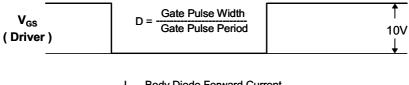
## **Unclamped Inductive Switching Test Circuit & Waveforms**

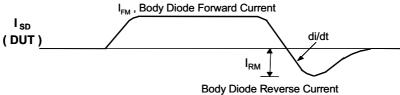


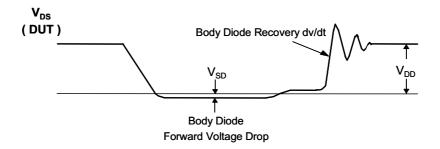


## Peak Diode Recovery dv/dt Test Circuit & Waveforms

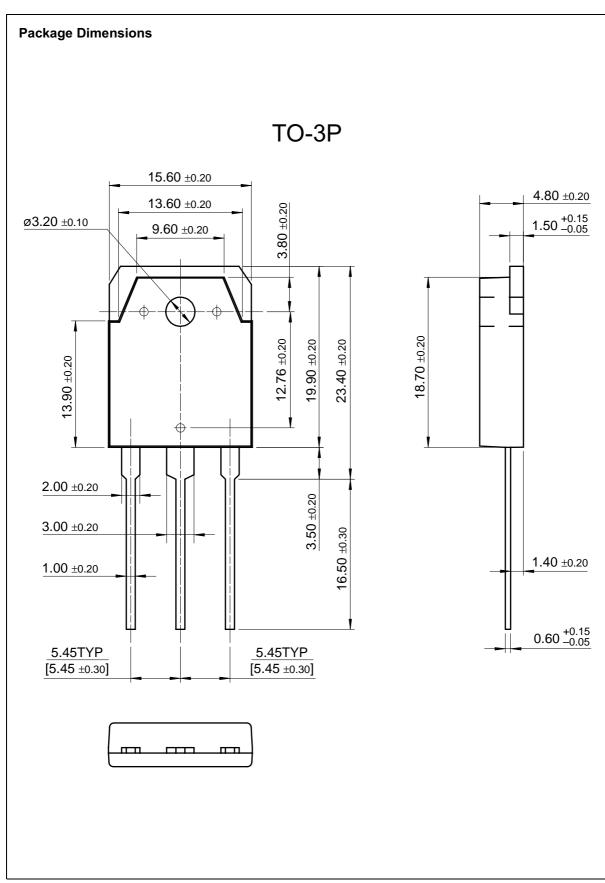








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